



LIST OF CITATIONS BY APPLICANT (use several sheets if necessary)	Atty. Docket No. 1673P1	10/627,776
	Applicant Stuart D. Hellring, et al.	
	Filing Date July 28, 2003	Group <u>1763</u>

U. S. PATENT DOCUMENTS

Exam. Init.		Document No.	Date	Name	Class	Subclass	Filing Date if appropriate
<i>GAG</i>	AA	5,720,551	02/24/98	T. Shechter	366	147	_____
<i>GAG</i>	AB	5,904,159	05/18/99	H. Kato, et al.	134	7	_____
	AC	5,980,775	11/09/99	S.K. Grumbine, et al.	252	79.1	_____
<i>GAG</i>	AD	6,136,711	10/24/00	S.K. Grumbine, et al.	438	692	_____
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		Document No.	Date	Country	Class	Subclass	Translation Yes	No
<i>GAG</i>	AL	WO 00/39056	06.07.00	PCT	_____	_____	<u>10</u>	_____
	AM							
	AN							
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OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>GAG</i>	AR	ASTM D 2414-93 "Standard Test Method for Carbon Black--n-Dibutyl Phthalate Absorption Number"
	AS	R.B. Anderson and P.H. Emmett, "Measurement of Carbon Black Particles by the Electron Microscope and Low Temperature Nitrogen Adsorption Isotherms", Journal of Applied Physics, Volume 19, April, 1948, pp. 367-373.
<i>GAG</i>	AT	ASTM D 1993-91 "Standard Test Method for Precipitated Silica-Surface Area by Multipoint BET Nitrogen Adsorption"

Examiner	George Goudreau	Date Considered
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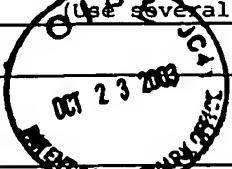
<i>gag</i>	AR	French Standard NF T 45-007, "Primary Materials for the Rubber Industry: Precipitated Hydrated Silica", Section 5.12, Method A, pp. 66-76, November 1987
	AS	Lee M. Cook, "Chemical Processes in Glass Polishing", Journal of Non-Crystalline Solids, 1990, 120, 152-171
<i>gag</i>	AT	Y. Li and S.V. Babu, "Chemical Mechanisms in CMP of Cu and Ta Using Silica Abrasives," Fifth Annual CMP Symposium 2000, August 14, 2000, Lake Placid, New York

Examiner	<i>George Goudreau</i>	Date Considered
		<i>10-051</i>

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SUBSTITUTE DISCLOSURE STATEMENT FORM (PTO 1449)

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	AN					
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OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>ggg</i>	AR	Y. Li, A. Jindal and S.V. Babu, "Role of Chemicals and Abrasive Particle Properties in Chemical-Mechanical Polishing of Copper and Tantalum, Proc." The Electrochemical Society 198 th Meeting, Phoenix, Arizona, October 22-27, 2000
<i>ggg</i>	AS	ASTM Standards, Method A of D-280, Volume 06.02 (Reapproved 1987) "Standard Test Methods for Hygroscopic Moisture (and Other Matter Volatile Under the Test Conditions) in Pigments"
<i>ggg</i>	AT	John H. Perry, Chemical Engineers Handbook, 4 th Edition, McGraw-Hill Book Company, New York (1963), Library of Congress Catalog Card Number 6113168, pages 8-42 and 8-43

Examiner	<i>George Gouldrean</i>	Date Considered
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10-051

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		Atty. Docket No. 1963P1	10/627,776
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OCT 23 2003		Filing Date July 28, 2003	Group 1763

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<i>ggg</i>	AR	Warren L. McCabe and Julian C. Smith, "Unit Operations of Chemical Engineering", 3 rd Edition, McGraw-Hill Book Company, New York (1976) ISBN 0-07-044825-6, pages 844-845
<i>ggg</i>	AS	F.E. Albus, "The Modern Fluid Energy Mill," Chemical Engineering Progress, Volume 60, No. 6 (June 1964), pages 102-106
<i>ggg</i>	AT	Ralph K. Iler, "The Chemistry of Silica," 1979 John Wiley & Sons, Inc., New York, Chapter 5

Examiner	George Goudreau	Date Considered
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AMERICAN TRADES & TRADEMARKS

U. S. PATENT DOCUMENTS

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OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

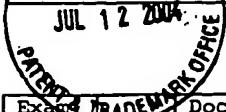
<i>Oppy</i>	AR	U.S. Serial No: 09/882,548 filed 06/12/02 "A SILICA-BASED SLURRY"
<i>Oppy</i>	AS	U.S. Serial No. 60/401,131 filed 08/05/02 "A SILICA-BASED SLURRY COMPOSITION"
<i>Oppy</i>	AT	U.S. Serial No. 60/401,108 filed 08/05/02 "CMP COMPOSITION AND SLURRY"

Examiner <i>George Gouldreau</i>	Date Considered <i>10-051</i>
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Examiner Init.	Document No.	Date	Name	Class	Subclass	Filing Date if appropriate
gag	AA 5,484,581	01/16/96	H. Esch, et al.	423	335	
gag	AB 6,063,306	05/16/00	V.B. Kaufman, et al.	252	79.4	
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		Document No.	Date	Country	Class	Subclass	Translation Yes	No
gag	AL	WO 97/45366	04.12.97	PCT				
gag	AM	WO 02/102910 A1	27.12.02	PCT				
gag	AN							
gag	AO							
gag	AP							

OTHER CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)

gag	AR	Silica and A Silica-Based Slurry, Stuart D. Hellring, et al., United States Patent Application Publication No. US 2003/0094593 A1
gag	AS	
gag	AT	

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George Goudreau	10-051

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